METHOD OF ETCHING A SEMICONDUCTOR DEVICE

Abstract

A method for etching windows 40 in a semiconductor device 10 having a metal fuse 14 embedded therein is disclosed. The method is for allowing accurate fuse blowing, in particular laser fuse blowing. The method involves the controlled removal of layers having different phase diffraction characteristics. After treatment, the remaining area between the metal fuse 14 and the etched surface of the semiconductor has substantially uniform phase diffraction characteristics.

Figure 3